

Structure of $W\text{Si}_n$ cage clusters probed by x-ray absorption fine structure spectra

H. Oyanagi¹, Z. H. Sun¹, N. Uchida², T. Miyazaki³ and T. Kanayama²

¹National Institute of Advanced Industrial Science and Technology, 1-1-1, Umezono, Tsukuba, Ibaraki, 305-8568, Japan

²Nanodevice Innovation Research Center, National Institute of Advanced Industrial Science and Technology, Tsukuba, Ibaraki 305-8562, Japan

³Quantum Modeling Group, Research Institute for Computational Sciences, National Institute of Advanced Industrial Science and Technology, Tsukuba, Ibaraki 305-8568, Japan

*e-mail: h.oyanagi@aist.go.jp

Transition metal -encapsulated Si cage clusters are expected to be able to stabilize Si cage structures which are promising building blocks for the fabrication of various nano- and optoelectronics devices [1]. We combined EXAFS and XANES to study the geometric arrangement of W around Si atoms in a series of $W\text{Si}_n$ cluster samples. The EXAFS results show similar radial distributions around W atoms in the $W\text{Si}_n$ samples and amorphous W-Si alloy, but the spatial distributions in the $W\text{Si}_n$ clusters and amorphous W-Si alloy quite different as revealed by detailed multiple-scattering XANES analysis. It is found that $W\text{Si}_8$ and $W\text{Si}_{12}$ cage clusters coexists in the as-deposited $W\text{Si}_n$ samples. The average fraction of $W\text{Si}_{12}$ cluster is evaluated to be 25%, 43%, and 45% for samples deposited in a SiH_4 pressure of 5, 0.5, and 0.1 Pa, respectively.

References

[1] H. Hiura, T. Miyazaki and T. Kanayama: *Phys. Rev. Lett.* **86**, 1733-1736 (2001).

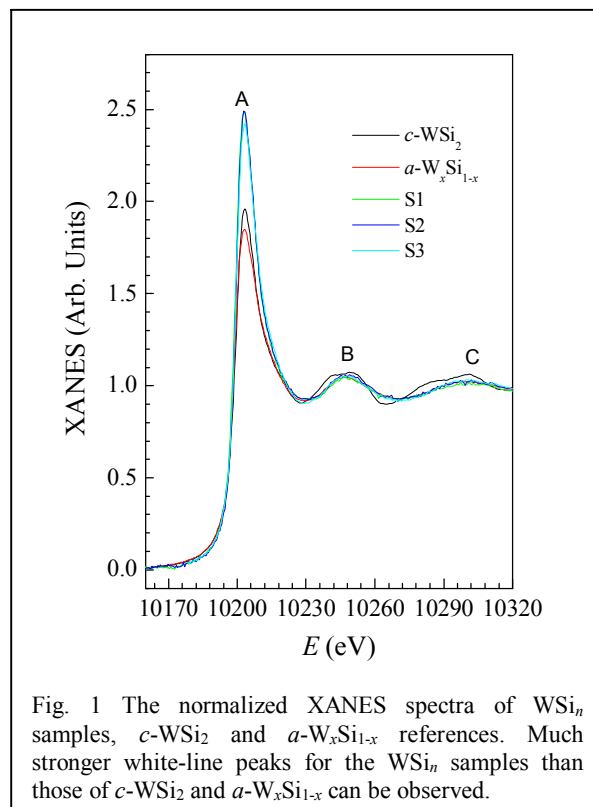


Fig. 1 The normalized XANES spectra of $W\text{Si}_n$ samples, $c\text{-WSi}_2$ and $a\text{-W}_x\text{Si}_{1-x}$ references. Much stronger white-line peaks for the $W\text{Si}_n$ samples than those of $c\text{-WSi}_2$ and $a\text{-W}_x\text{Si}_{1-x}$ can be observed.